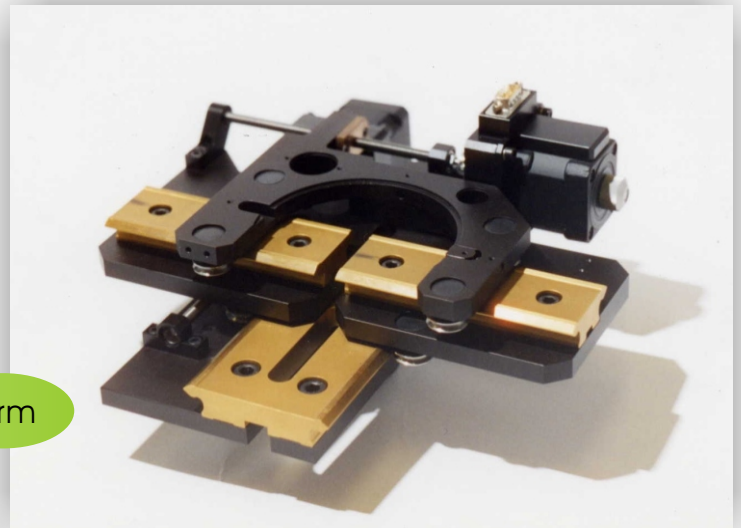


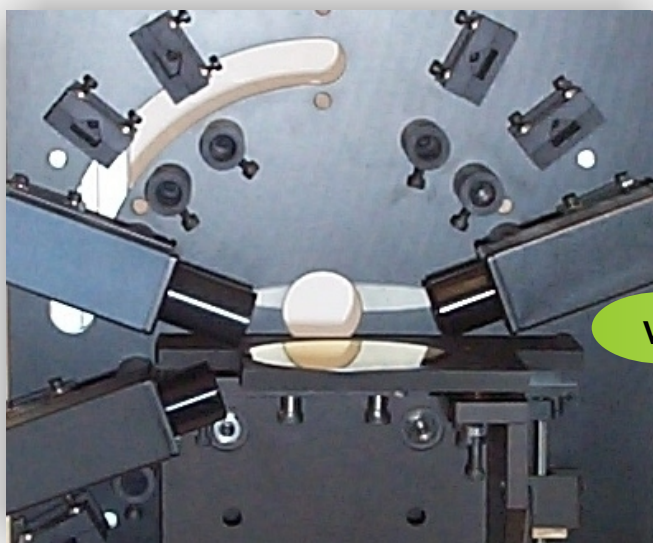
This option for the nkd – 8000 only, provides the facility to vary the angle of incidence from 0 to 90 degrees and from 20 to 70 degrees when measuring T and R simultaneously. The transmitted light detector is mounted on the same moving arm as the incident beam and therefore moves with it. The reflected light detector is mounted on a separate mechanism and moves at an angle equal to the incident beam or independently depending on programming. The variable angle option is a powerful feature and is fully computer controlled. It opens up the opportunity to easily characterise, beam splitters, laser mirrors and complex coatings.

VA00760: Variable Angle Motorised Beam and Detectors

Fully automatic mapping of samples up to 100x100mm is possible with the X Y mapping platform. The unique design ensures movement in both x and y whilst maintaining a clear aperture through the center. It also includes a set position for the reference sample for automatic calibration. The stage is fully motorised and features an ultra compact robust design. A range of sample adaptor inserts is available to suit most applications. Manual control of the stage is also possible.



TS00525: X Y Mapping Platform



The multiple angle option features a choice of 3 fixed incident beam positions. These are 30, 50 and 70 degrees or any customer specified angle. On the standard instrument a single fixed angle of 30 degrees is provided. The multiple angle option is available on all models.

VA00750: Multiple Angle

Aquila supply a range of photodetectors, covering the spectrum from 190nm to the mid infrared (Si, InGaAs, Pbs, Ge, Thermopile). Their sturdy construction and innovative design, enable excellent photometric performance, low noise and high sensitivity. Convenient packaging allows standard optical accessories to be screwed to the detector, such as lenses and filters.



PD00XXX: Detectors



Aquila manufacture a range of sample inserts for convenient mounting of typical thin film samples.

IN00XXX: Sample Inserts - Various

Sample temperature control can be achieved with the use of the heated sample chuck. And T and R spectra can be measured over a range of temperatures.



TC150: Heated Sample Chuck



MS00770: Microspot Beam

This device focuses incident beam light down to spot sizes of 200um, providing the capability to identify and characterise very small areas. The Computer control provides high precision focusing and as with all Aquila accessories, its construction is robust and high quality. The microspot has applications in pixel characterisation, small sample analysis and the analysis of highly inconsistent films.

Select s-, p- or unpolarised incident light with the click of a mouse, using the automatic polarisation selector. Standard instruments have a manual dial for choosing the polarisation state.

POL820: Automatic Polariser



RS00900: Rotation Stage

The rotation stage option is specifically designed for very high accuracy, large or cantilever load applications and can be used in OEM applications.

An optional bench/storage pedestal is available for mounting the nkd system in a more industrial environment. The PC supplied with a system having this option is an Industrial PC. A convenient drawer is provided and there is adequate space for manual and sample storage.



PED810: Pedestal